

## IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF

JAMAL RAMDANI ET AL

: EXAMINER: MUNSON, G. M.

9/a FJONES 11-502

SERIAL NO: 09/766,046

FILED: JANUARY 19, 2001

: GROUP ART UNIT: 2811

117500

FOR: STRUCTURE AND METHOD FOR: FABRICATING GaN DEVICES UTILIZING THE FORMATION OF A COMPLIANT SUBSTRATE

RECEIVED

## **AMENDMENT**

ASSISTANT COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

SIR:

Responsive to the Official Action dated April 30, 2002, Applicants respectfully request reconsideration in view of the following amendment and remarks.

## IN THE CLAIMS

## Please amend Claim 1 as follows:

- 1. (Amended) A semiconductor structure comprising:
- a monocrystalline substrate;
- an amorphous layer formed on the substrate; and
- a first monocrystalline nitride material layer overlying the amorphous layer and formed of at least one selected from the group consisting of GaN, GaInN, AlGaN, SiN and AlN, wherein the first monocrystalline nitride material layer is formed by nitridation of a first

